

<b>Notice of References Cited</b>	Application/Control No. 09/608,743	Applicant(s)/Patent Under Reexamination HEIN ET AL.	
	Examiner Walter F. Briney III	Art Unit 2615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sedra et al., Microelectronic Circuits, Fourth Edition Oxford University Press 23-24 (1998).
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